Notice of References Cited

Application/Control No.	Applicant(s)/Pater Reexamination	nt Under
10/020,638	MA ET AL.	
Examiner	Art Unit	
James Mitchell	2827	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,388,321	05-2002	Hirai et al.	174/259
	В	US-5,494,981	02-1996	Gorodisher et al.	525/504
	ပ	US-6,331,446	12-2001	Cook et al.	438/106
	D	US-			
	E	US-			
	F	US-		·	
	G	US-			
	Н	US-			
	l	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	200225211	07-2001	Japan	Chun	
	0	62-275123	11-1987	Japan	Toray	
	Р					
	Q					
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	L. Nguyen, "Solder Joint Shape Formation Under Constrained Boundaries in Wafer Level Underfill", 2000 IEEE
	v	
	w	
	х	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.